



PTO/SB/08a/b (07-05)

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<b>Substitute for form 1449A/B/PTO</b>  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)			<b>Complete If Known</b>		
			Application Number	10/825007-Conf. #7251	
			Filing Date	April 15, 2004	
			First Named Inventor	Ryan J. BERG	
			Art Unit	2192	
			Examiner Name	E. B. Kiss	
Sheet	1	of	2	Attorney Docket Number	0286685.00124US1

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)				

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NON PATENT LITERATURE DOCUMENTS						
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				T <sup>2</sup>
EBK	CA	ASHCRAFT, et al., "Using Programmer-Written Compiler Extensions to Catch Security Holes", IEEE Symposium on Security and Privacy, Oakland, CA, May 2002				
EBK	CB	BUSH, et al., "A Static Analyzer for Finding Dynamic Programming Errors", Software - Practice and Experience, Vol. 30, No. 7, 2000				
EBK	CC	DOR, et al., "Cleanness Checking of String Manipulations in C Programs via Integer Analysis", 8th International Symposium on Static Analysis (SAS), pp. 194-212, July 2001				
EBK	CD	DOR, et al., "CSSV: Towards a Realistic Tool for Statically Detecting All Buffer Overflows in C", PLDI '03, June 9-11, 2003, San Diego, California				
EBK	CE	FOSTER, et al., "A Theory of Type Qualifiers", Programming Language Design and Implementation (PLDI'99), pp. 192-203, Atlanta, GA, May 1999				
EBK	CF	GANAPATHY, et al., "Buffer Overrun Detection Using Linear Programming and Static Analysis", CCS '03, October 27-30, 2003, Washington, DC				
	<del>CG</del>	<del>HAUGH, et al., "Testing C Programs for Buffer Overflow Vulnerabilities", Proceedings of the 2000 Symposium on Networked and Distributed System Security (SNDSS 2000), February 2000</del>				
EBK	CH	LARUS, et al., "Righting Software", IEEE Software, May/June 2004, pp. 92-100				
EBK	CI	LHEE, et al., "Type-Assisted Dynamic Buffer Overflow Detection", 11th USENIX Security Symposium, pp. 81-88, August 2002				
EBK	CJ	SIMON, et al., "Analyzing String Buffers in C", International Conference on Algebraic Methodology and Software Technology, Vol. 2422 of Lecture Notes in Computer Science (H. Krichner and C. Ringeissen, Eds.) (Springer), pp. 365-379, September 2002				
EBK	CK	RUGINA, et al., "Symbolic Bounds Analysis of Pointers, Array Indices, and Accessed Memory Regions", ACM Transactions of Programming Languages and Systems, Vol. 27, No. 2, pp., 185-234, 2005				
	<del>CL</del>	<del>GHANIKAR, et al., "Detecting Format String Vulnerabilities with Type Qualifiers", Proceedings of the 10th USENIX Security Symposium, Washington, DC, August 2001 (Date appearing on first page of the document is May 11, 2001)</del>				

Examiner Signature	/Eric B. Kiss/	Date Considered	05/10/2006
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EBK	CM	XIE, et al., "ARCHER: Using Symbolic, Path-sensitive Analysis to Detect Memory Access Errors", ESEC/FSE '03, September 1-5, 2003, Helsinki, Finland	
EBK	CN	XU, et al., "An Efficient and Backwards-Compatible Transformation to Ensure Memory Safety of C Programs", SIGSOFT '04/FSE-12, October 31-November 6, 2004, Newport Beach, CA	

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